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Tables of Contents

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edge <and> closed <and> mask

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Tables of Contents

○- Journals
   & Magazines
○- Conference
   Proceedings
○- Standards

Search

○- By Author
○- Basic
○- Advanced
○- CrossRef

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```
edge <and> polygon <and> mask
```

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Tables of Contents

◯- **Journals & Magazines**
◯- **Conference Proceedings**
◯- **Standards**

Search

◯- **By Author**
◯- **Basic**
◯- **Advanced**
◯- **CrossRef**

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```
gradient <and> closed <and>
mask
```

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○- Home
○- What Can
   I Access?
○- Log-out

Tables of Contents

○- Journals
   & Magazines
○- Conference
   Proceedings
○- Standards

Search

○- By Author
○- Basic
○- Advanced
○- CrossRef

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| gradient <and> polygon* <and> mask | | Search |

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Tables of Contents

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   & Magazines
○ Conference
   Proceedings
○ Standards

Search

○ By Author
○ Basic
○ Advanced
○ CrossRef

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```
(gradient <or> edge) <and>
polygon* <and> (extract* <or>
segment*)
```

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